

Search Notes

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10/705,763

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

CLARK ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	10/19/2006	CH
455	418	10/19/2006	CH
705	1	10/19/2006	CH
705	59	10/19/2006	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	10/19/2006	CH
Combined Text	10/19/2006	CH